

Notice of References Cited	Application/Control No. 10/717,488		Applicant(s)/Patent Under Reexamination LIN, WEN-CHIH	
	Examiner Nathan Mitchell		Art Unit 2617	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0174335 A1	11-2002	Zhang et al.	713/168
*	B	US-2003/0051041 A1	03-2003	Kalavade et al.	709/229
*	C	US-2003/0158722 A1	08-2003	Lord, John Raymond	704/3
*	D	US-6,694,134 B1	02-2004	Lu et al.	455/419
*	E	US-2004/0162105 A1	08-2004	Reddy et al.	455/551
*	F	US-7,075,912 B2	07-2006	Suda et al.	370/331
*	G	US-7,107,620 B2	09-2006	Haverinen et al.	726/29
*	H	US-7,127,234 B2	10-2006	Ishii, Yoshikazu	455/411
*	I	US-7,171,460 B2	01-2007	Kalavade et al.	709/223
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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